



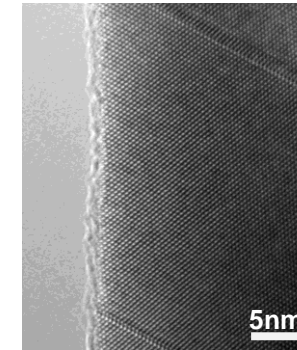
Nicholas G. Rudawski, *Associate Engineer*

Nicholas G. Rudawski received his B.S.E. degree in Materials Science and Engineering from the University of Michigan in 2005 and his Ph.D. degree in Materials Science and Engineering from the University of Florida in 2008. He joined the Research Service Centers in August of 2012 as service/teaching faculty, where he oversees training, operation, and maintenance of the scanning/transmission electron microscopes and dual beam FIB/SEM systems. He has authored or coauthored more than 50 electron microscopy-related peer-reviewed publications since 2003.

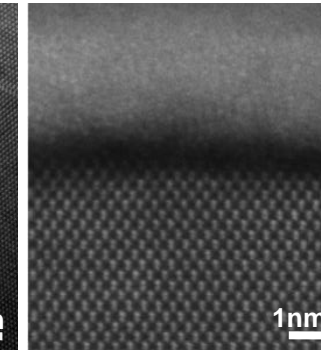


Scanning/Transmission Electron Microscopy

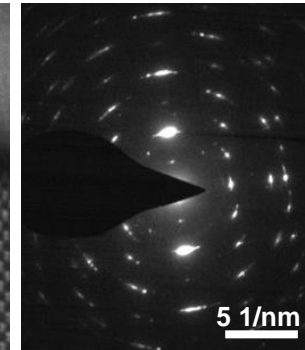
HR-TEM



HAADF-STEM

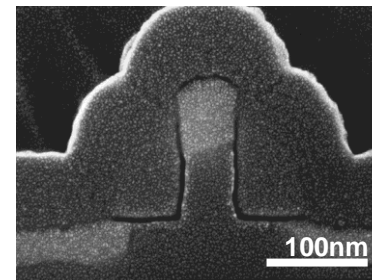
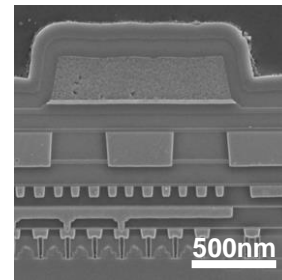
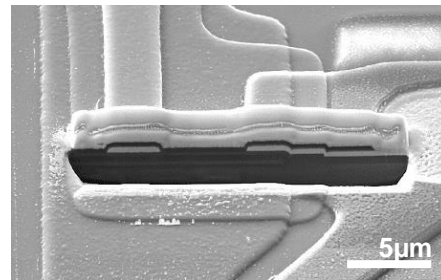


SAED

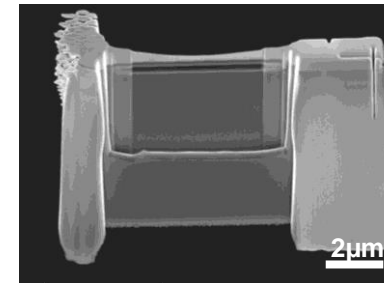
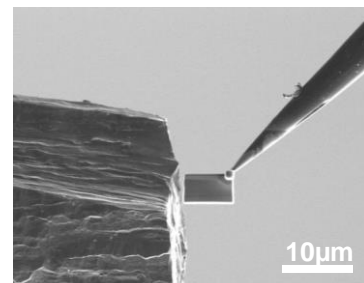
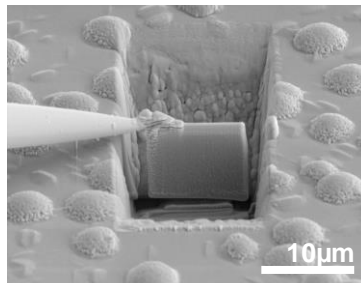


Dual beam focused ion beam/scanning electron microscopy

Site-Specific High-Resolution Cross-Sectional SEM Imaging



Site-Specific S/TEM Specimen Preparation Via In-Situ Lift-Out



EDS (Characteristic X-ray) Mapping

